

Notice of References Cited

Application/Control No.

10/074,141

Applicant(s)/Patent Under

Reexamination

BAJAJ ET AL.

Examiner

Edna Wong

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Art Unit

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-4,282,271	08-1981	Feldstein, Nathan	427/98
	C	US-			
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	M	US-			

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

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